

## Features

- Single element PIN-Diode
- High QE in the visible spectrum
- Flip chip design for flat surface
- Chip size package
- Reflow solderable, MSL1

## Description

Backside illuminated PIN photodiode optimized for CsI:Tl scintillator luminescence detection. BGA package with flat surface flip chip design.

## Application

- X-ray inspection
- Photometry
- Array assemblies

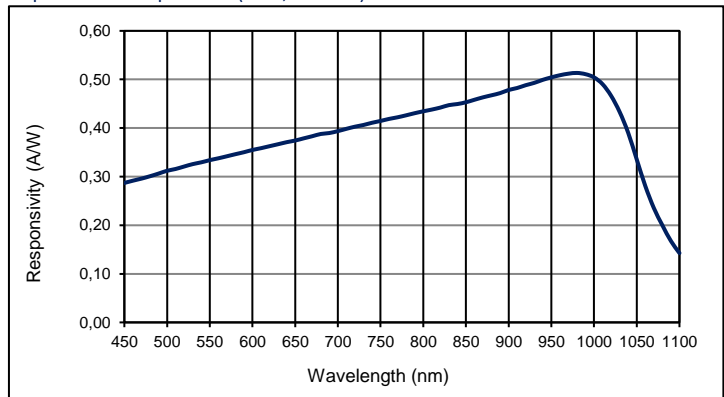
## RoHS

2011/65/EU

## Absolute maximum ratings

| Symbol      | Parameter         | Min | Max | Unit |
|-------------|-------------------|-----|-----|------|
| $T_{STG}$   | Storage temp      | -20 | 80  | °C   |
| $T_{OP}$    | Operating temp    | -10 | 60  | °C   |
| $V_{R(OP)}$ | Operating voltage | -   | 10  | V    |
| $I_{PEAK}$  | Peak DC current   |     | 10  | mA   |

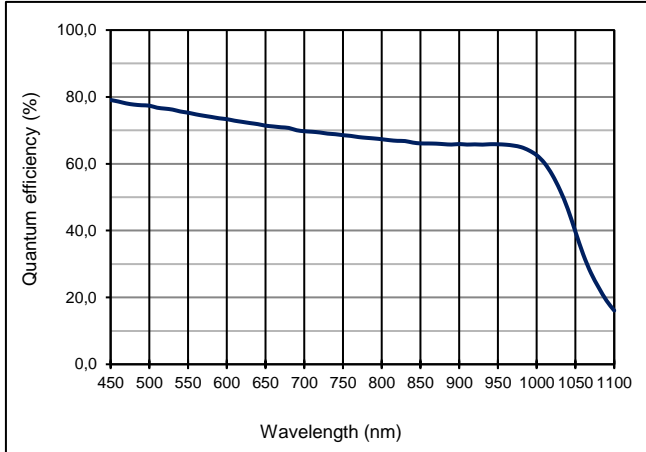
## Spectral response (0 V, 23 °C)



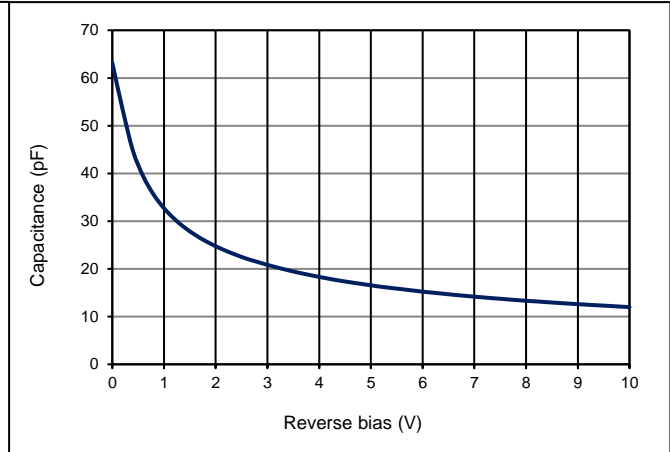
## Electro-optical characteristics @ 23 °C

| Symbol   | Characteristic    | Test Condition   | Min | Typ         | Max      | Unit            |
|----------|-------------------|--|-----|-------------|----------|-----------------|
|          | No of elements    |  |     | 1           |          |                 |
|          | Chip area         |  |     | 2800 x 2800 |          | $\mu\text{m}^2$ |
|          | Diode area        |  |     | 6.211       |          | $\text{mm}^2$   |
| $I_D$    | Dark current      | $U_R = 10 \text{ mV}$ ; per element                                  |     | 15          | 100      | pA              |
|          |                   | $U_R = 10 \text{ V}$ ; per element                                   |     | 250         | 2000     | pA              |
| $C$      | Capacitance       | $U_R = 0 \text{ V}$ ; per element                                    |     | 65          | 80       | pF              |
|          |                   | $U_R = 10 \text{ V}$ ; per element                                   |     | 12          |          | pF              |
|          | Responsivity      | $U_R = 0 \text{ V}$ ; $\lambda = 490 \text{ nm}$                     |     | 0.30        |          | A/W             |
|          |                   | $U_R = 0 \text{ V}$ ; $\lambda = 540 \text{ nm}$                     |     | 0.33        |          | A/W             |
| $t_R$    | Rise time         | $U_R = 0 \text{ V}$ ; $\lambda = 540 \text{ nm}$ ; $R_L = 50 \Omega$ |     | 25          |          | $\mu\text{s}$   |
| $R_{Sh}$ | Shunt resistance  | $U_R = 10 \text{ mV}$  | 100 | 666         |          | M $\Omega$      |
| $V_{BR}$ | Breakdown voltage | $I_R = 2 \mu\text{A}$  | 10  | 15          |          | V               |
|          | N.E.P.            | $V_R = 10 \text{ mV}$ ; $\lambda = 540 \text{ nm}$                   |     | 6.6 E-15    | 1.7 E-14 | W/Hz            |

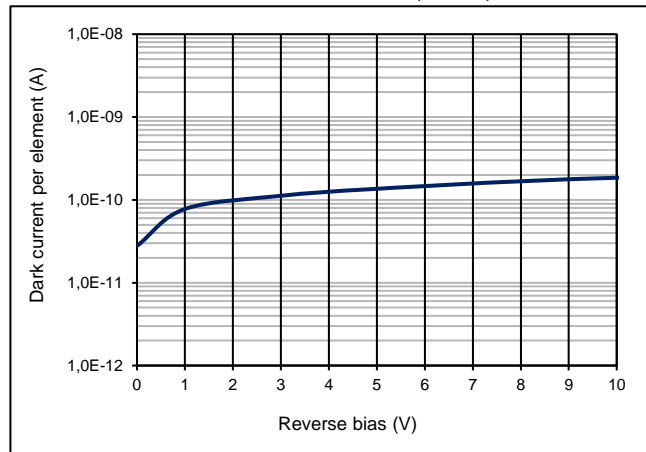
Quantum efficiency (23 °C)



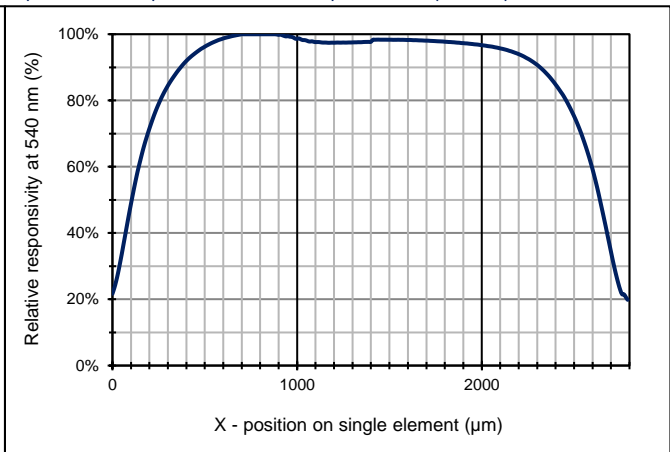
Capacitance as fct of reverse bias (23 °C)



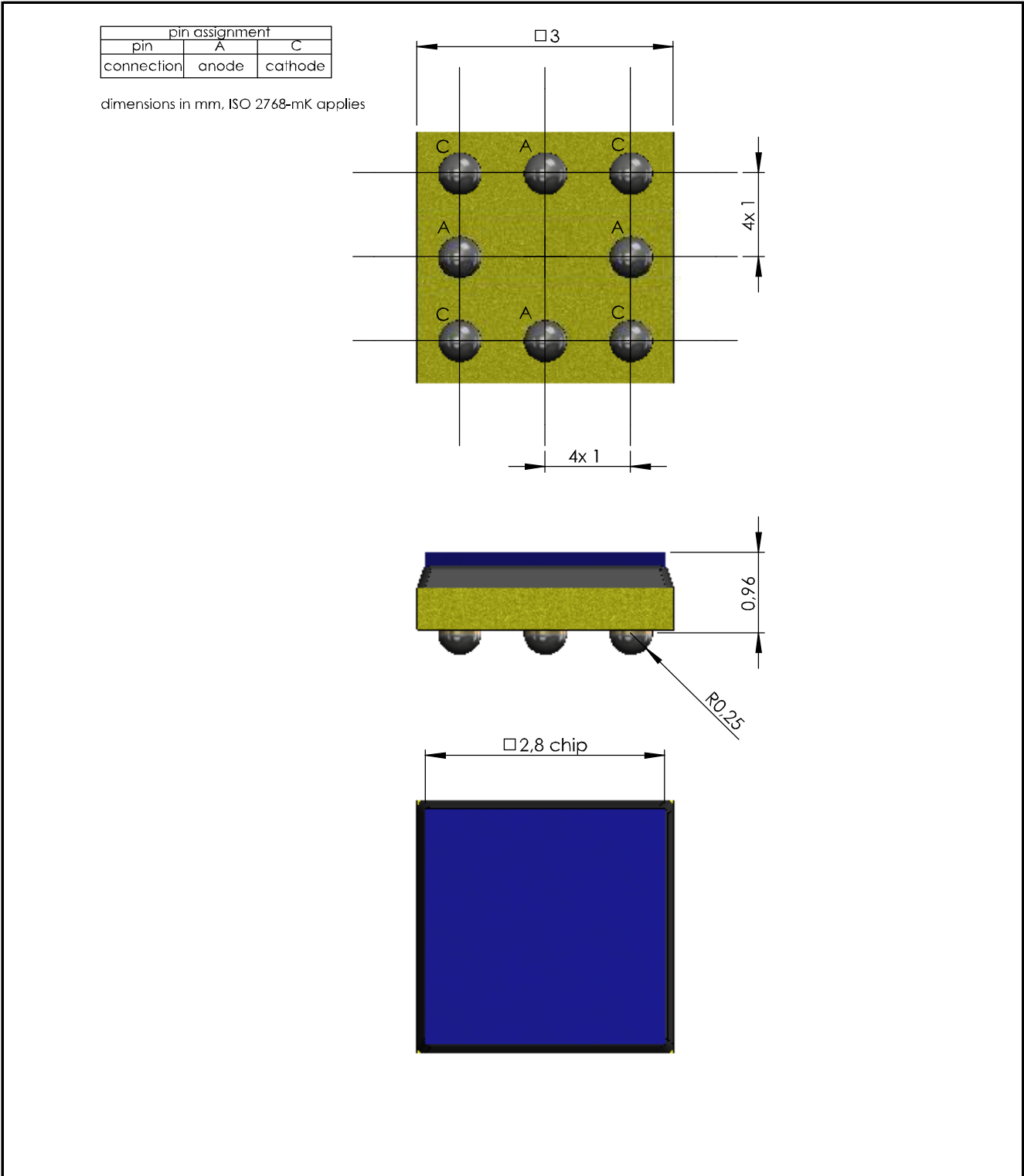
Dark current as fct of reverse bias (23 °C)



Spectral response as fct of position (23 °C)



Technical Drawing Package:



Handling: Please refer to document "Instructions for handling and processing"

Disclaimer: Due to our strive for continuous improvement, specifications are subject to change within our PCN policy according to JESD46C.